

Toluene
CMOS



Material No.: 9466-03
Batch No.: 0000215880
Manufactured Date: 2018/11/26
Retest Date: 2023/11/25
Revision No: 1

Certificate of Analysis

Test	Specification	Result
Assay (C ₆ H ₅ CH ₃) (by GC)	>= 99.5 %	99.9
Color (APHA)	<= 10	5
Acidity (µeq/g)	<= 0.2	< 0.1
Residue after Evaporation	<= 2.0 ppm	< 1.0
Water (by KF, coulometric)	<= 0.03 %	0.01
Substances Darkened by H ₂ SO ₄	Passes Test	PT
Sulfur Compounds (as S)	<= 0.003 %	< 0.001
Chloride (Cl)	<= 2 ppm	< 2
Phosphate (PO ₄)	<= 0.5 ppm	< 0.5
Trace Impurities – Aluminum (Al)	<= 20.0 ppb	< 5.0
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Trace Impurities – Barium (Ba)	<= 10.0 ppb	< 1.0
Trace Impurities – Boron (B)	<= 20.0 ppb	< 5.0
Trace Impurities – Cadmium (Cd)	<= 20.0 ppb	< 1.0
Trace Impurities – Calcium (Ca)	<= 100.0 ppb	3.3
Trace Impurities – Chromium (Cr)	<= 10.0 ppb	< 1.0
Trace Impurities – Cobalt (Co)	<= 20.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 20.0 ppb	< 1.0
Trace Impurities – Gallium (Ga)	<= 50.0 ppb	< 1.0
Trace Impurities – Germanium (Ge)	<= 50.0 ppb	< 10.0
Trace Impurities – Gold (Au)	<= 20.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 500 ppb	< 500
Trace Impurities – Iron (Fe)	<= 20.0 ppb	< 1.0
Trace Impurities – Lithium (Li)	<= 20.0 ppb	< 1.0

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.386.1700
Avantor Performance Materials, LLC
100 Matsonford Rd, Suite 200, Radnor, PA 19087. U.S.A. Phone: 610.386.1700

Test	Specification	Result
Trace Impurities – Magnesium (Mg)	<= 10.0 ppb	< 1.0
Trace Impurities – Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities – Nickel (Ni)	<= 20.0 ppb	< 5.0
Trace Impurities – Potassium (K)	<= 50.0 ppb	< 10.0
Trace Impurities – Silicon (Si)	<= 100.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 20.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 100.0 ppb	< 5.0
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities – Tin (Sn)	<= 30.0 ppb	< 10.0
Trace Impurities – Zinc (Zn)	<= 20.0 ppb	< 1.0
Particle Count – 1.0 µm and greater	<= 10 par/ml	4

For Microelectronic Use

Country of Origin: US
Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2015, FSSC22000
 Paris, KY 9001:2008
 Mexico City, Mexico 9001:2008
 Gliwice, Poland 9001:2015, 13485:2012
 Selangor, Malaysia 9001:2008
 Dehradun, India, 9001:2008, 14001:2004, 13485:2003
 Mumbai, India, 9001:2015, 17025:2005
 Panoli, India 9001:2015



Jamie Ethier
 Vice President Global Quality

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